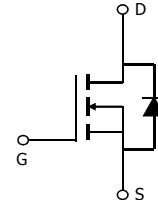


General Description

The AOT298L & AOB298L & AOTF298L uses Trench MOSFET technology that is uniquely optimized to provide the most efficient high frequency switching performance. Power losses are minimized due to an extremely low combination of $R_{DS(ON)}$ and C_{rss} . In addition, switching behavior is well controlled with a soft recovery body diode. This device is ideal for boost converters and synchronous rectifiers for consumer, telecom, industrial power supplies and LED backlighting.

Features

V_{DS}	100V
I_D (at $V_{GS}=10V$)	58A/33A
$R_{DS(ON)}$ (at $V_{GS}=10V$)	< 14.5mΩ



Absolute Maximum Ratings $T_A=25^\circ\text{C}$ unless otherwise noted

Parameter	Symbol	AOT298L/AOB298L	AOTF298L	Units
Drain-Source Voltage	V_{DS}	100		V
Gate-Source Voltage	V_{GS}	± 20		V
Continuous Drain Current	I_D	58	33	A
$T_C=100^\circ\text{C}$		41	26	
Pulsed Drain Current ^C	I_{DM}	130		
Continuous Drain Current	I_{DSM}	9		A
$T_A=70^\circ\text{C}$		7		
Avalanche Current ^C	I_{AS}, I_{AR}	20		A
Avalanche energy $L=0.1\text{mH}$ ^C	E_{AS}, E_{AR}	20		mJ
Power Dissipation ^B	P_D	100	33	W
$T_C=100^\circ\text{C}$		50	16	
Power Dissipation ^A	P_{DSM}	2.1		W
$T_A=70^\circ\text{C}$		1.33		
Junction and Storage Temperature Range	T_J, T_{STG}	-55 to 175		°C

Thermal Characteristics

Parameter	Symbol	AOT298L/AOB298L	AOTF298L	Units
Maximum Junction-to-Ambient ^A $t \leq 10\text{s}$	$R_{\theta JA}$	15	15	°C/W
Maximum Junction-to-Ambient ^{A,D} Steady-State		60	60	°C/W
Maximum Junction-to-Case	$R_{\theta JC}$	1.5	4.5	°C/W

Electrical Characteristics ($T_J=25^\circ\text{C}$ unless otherwise noted)

Symbol	Parameter	Conditions	Min	Typ	Max	Units
STATIC PARAMETERS						
BV_{DSS}	Drain-Source Breakdown Voltage	$I_D=250\mu\text{A}, V_{GS}=0\text{V}$	100			V
I_{DSS}	Zero Gate Voltage Drain Current	$V_{DS}=100\text{V}, V_{GS}=0\text{V}$ $T_J=55^\circ\text{C}$			1 5	μA
I_{GSS}	Gate-Body leakage current	$V_{DS}=0\text{V}, V_{GS}=\pm20\text{V}$			±100	nA
$V_{GS(\text{th})}$	Gate Threshold Voltage	$V_{DS}=V_{GS}, I_D=250\mu\text{A}$	2.7	3.3	4.1	V
$I_{D(\text{ON})}$	On state drain current	$V_{GS}=10\text{V}, V_{DS}=5\text{V}$	130			A
$R_{DS(\text{ON})}$	Static Drain-Source On-Resistance	$V_{GS}=10\text{V}, I_D=20\text{A}$ $T_J=125^\circ\text{C}$		12 19	14.5 24	$\text{m}\Omega$
g_{FS}	Forward Transconductance	$V_{DS}=5\text{V}, I_D=20\text{A}$		30		S
V_{SD}	Diode Forward Voltage	$I_S=1\text{A}, V_{GS}=0\text{V}$		0.7	1	V
I_S	Maximum Body-Diode Continuous Current ^G				70	A
DYNAMIC PARAMETERS						
C_{iss}	Input Capacitance	$V_{GS}=0\text{V}, V_{DS}=50\text{V}, f=1\text{MHz}$		1250	1670	pF
C_{oss}	Output Capacitance			727	970	pF
C_{rss}	Reverse Transfer Capacitance			25	43	pF
R_g	Gate resistance	$V_{GS}=0\text{V}, V_{DS}=0\text{V}, f=1\text{MHz}$		2	3	Ω
SWITCHING PARAMETERS						
$Q_g(10\text{V})$	Total Gate Charge	$V_{GS}=10\text{V}, V_{DS}=50\text{V}, I_D=20\text{A}$		19	27	nC
Q_{gs}	Gate Source Charge			5.5		nC
Q_{gd}	Gate Drain Charge			6		nC
$t_{D(\text{on})}$	Turn-On DelayTime	$V_{GS}=10\text{V}, V_{DS}=50\text{V}, R_L=2.5\Omega, R_{GEN}=3\Omega$		7.5		ns
t_r	Turn-On Rise Time			14		ns
$t_{D(\text{off})}$	Turn-Off DelayTime			15		ns
t_f	Turn-Off Fall Time			14		ns
t_{rr}	Body Diode Reverse Recovery Time	$I_F=20\text{A}, dI/dt=500\text{A}/\mu\text{s}$		39		ns
Q_{rr}	Body Diode Reverse Recovery Charge	$I_F=20\text{A}, dI/dt=500\text{A}/\mu\text{s}$		140		nC

A. The value of R_{QJA} is measured with the device mounted on 1in² FR-4 board with 2oz. Copper, in a still air environment with $T_A=25^\circ\text{C}$. The Power dissipation P_{DSM} is based on R_{QJA} and the maximum allowed junction temperature of 150°C . The value in any given application depends on the user's specific board design, and the maximum temperature of 175°C may be used if the PCB allows it.

B. The power dissipation P_D is based on $T_{J(\text{MAX})}=175^\circ\text{C}$, using junction-to-case thermal resistance, and is more useful in setting the upper dissipation limit for cases where additional heatsinking is used.

C. Repetitive rating, pulse width limited by junction temperature $T_{J(\text{MAX})}=175^\circ\text{C}$. Ratings are based on low frequency and duty cycles to keep initial $T_J=25^\circ\text{C}$.

D. The R_{QJA} is the sum of the thermal impedance from junction to case R_{QJC} and case to ambient.

E. The static characteristics in Figures 1 to 6 are obtained using <300μs pulses, duty cycle 0.5% max.

F. These curves are based on the junction-to-case thermal impedance which is measured with the device mounted to a large heatsink, assuming a maximum junction temperature of $T_{J(\text{MAX})}=175^\circ\text{C}$. The SOA curve provides a single pulse rating.

G. The maximum current limited by package.

H. These tests are performed with the device mounted on 1 in² FR-4 board with 2oz. Copper, in a still air environment with $T_A=25^\circ\text{C}$.



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AOT298L/AOB298L/AOTF298L

100V N-Channel MOSFET

TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS

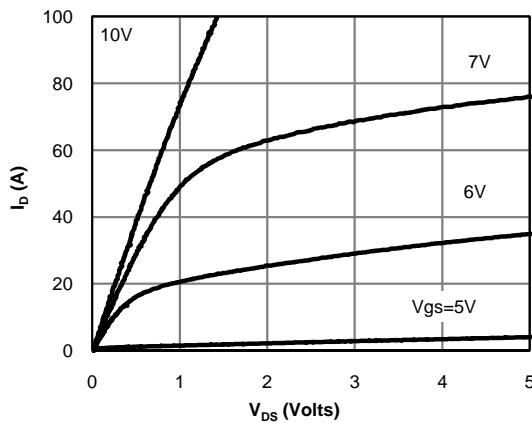


Fig 1: On-Region Characteristics (Note E)

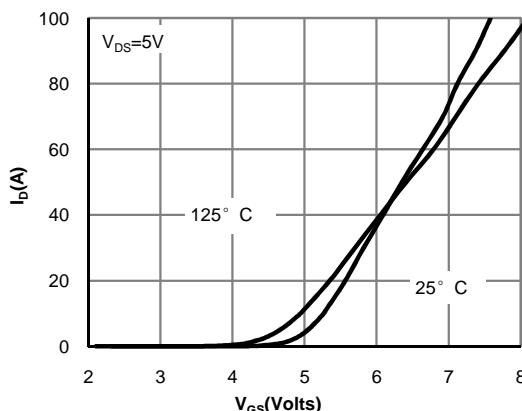


Figure 2: Transfer Characteristics (Note E)

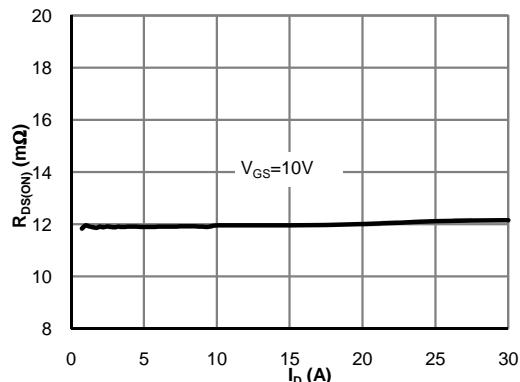


Figure 3: On-Resistance vs. Drain Current and Gate Voltage (Note E)

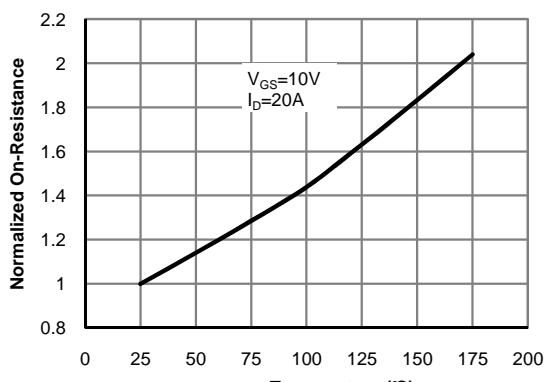


Figure 4: On-Resistance vs. Junction Temperature (Note E)

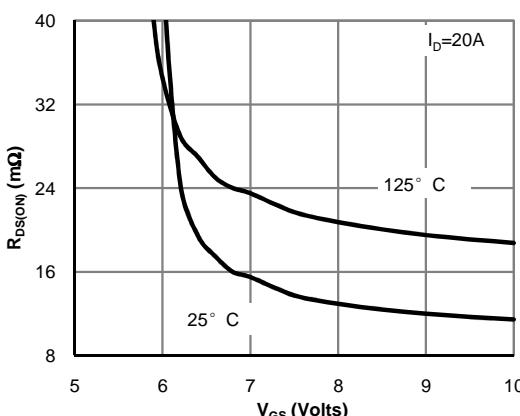


Figure 5: On-Resistance vs. Gate-Source Voltage (Note E)

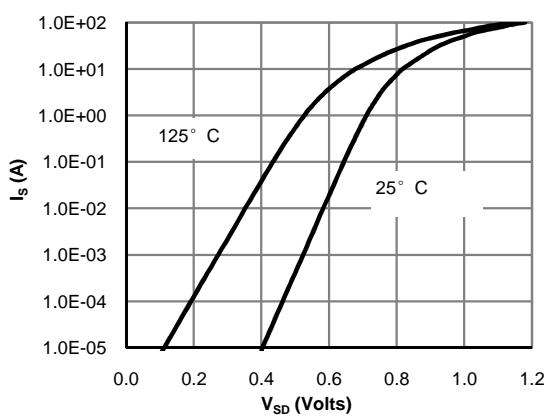


Figure 6: Body-Diode Characteristics (Note E)

TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS

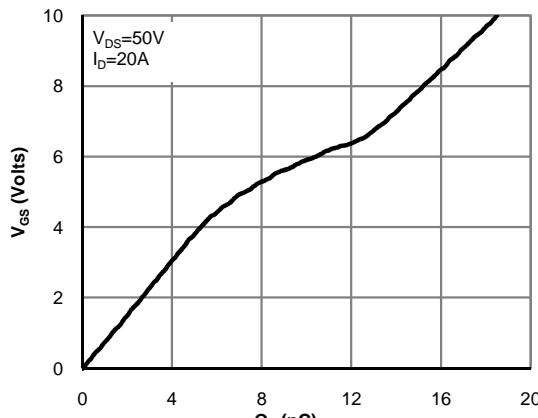


Figure 7: Gate-Charge Characteristics

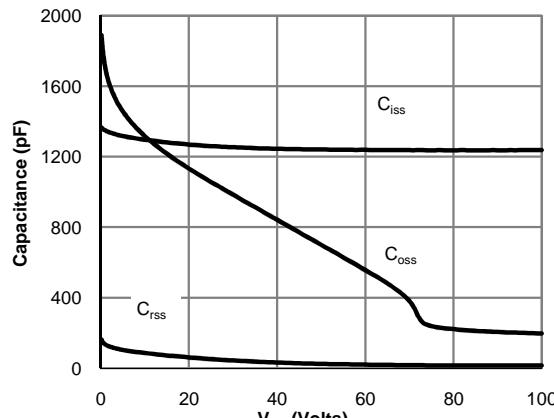


Figure 8: Capacitance Characteristics

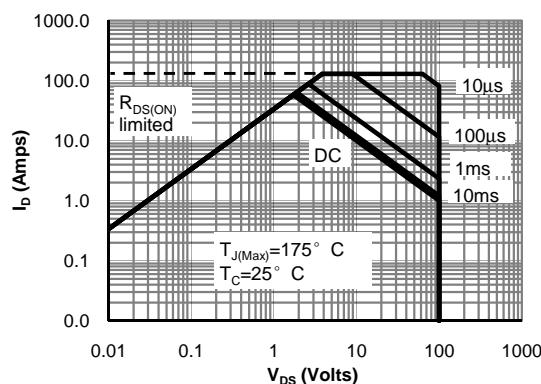


Figure 9: Maximum Forward Biased Safe Operating Area for AOT298L and AOB298L (Note F)

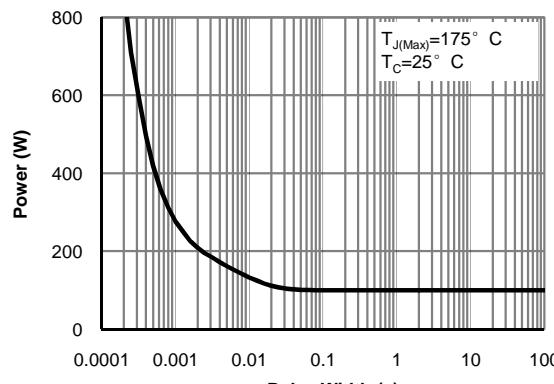
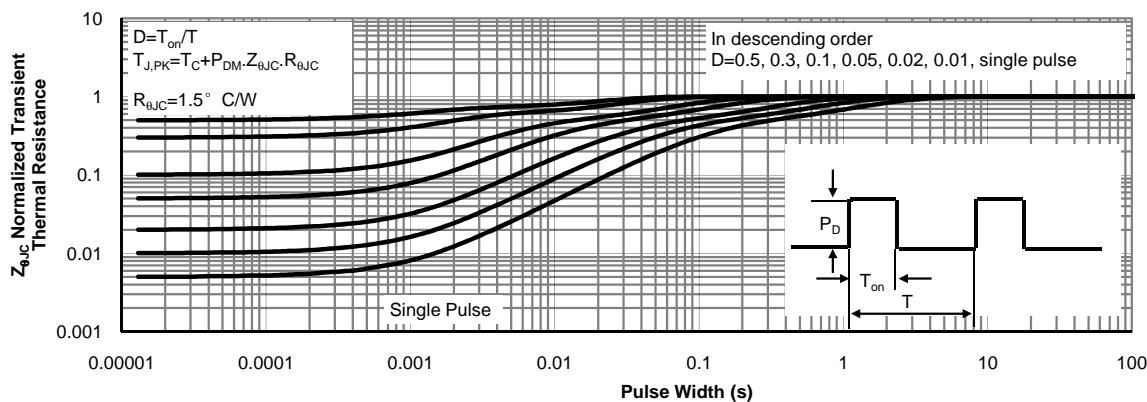


Figure 10: Single Pulse Power Rating Junction-to-Case for AOT298L and AOB298L (Note F)





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AOT298L/AOB298L/AOTF298L

100V N-Channel MOSFET

TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS

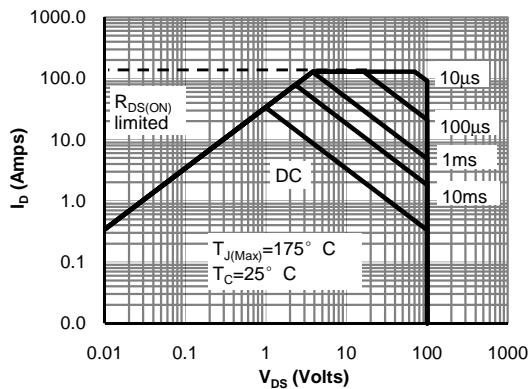


Figure 12: Maximum Forward Biased Safe Operating Area for AOTF298L (Note F)

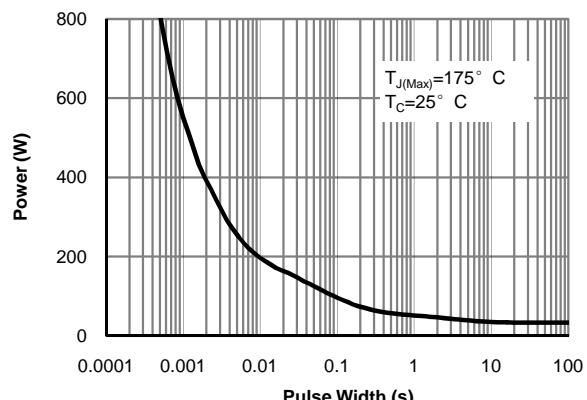


Figure 13: Single Pulse Power Rating Junction-to-Case for AOTF298L (Note F)

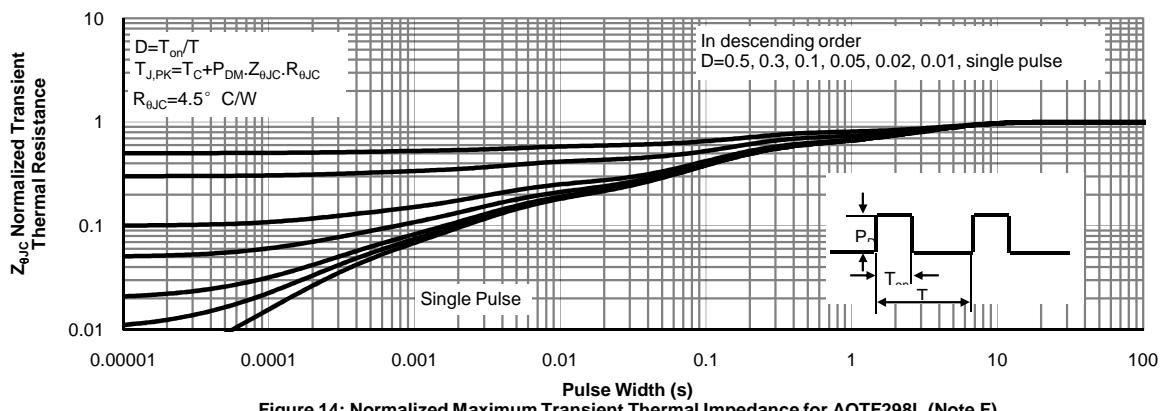


Figure 14: Normalized Maximum Transient Thermal Impedance for AOTF298L (Note F)

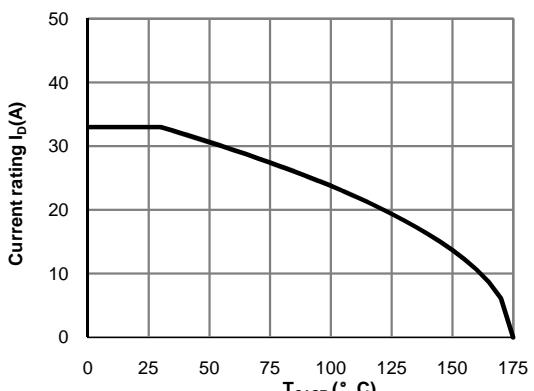


Figure 15: Current De-rating for AOTF298 (Note F)

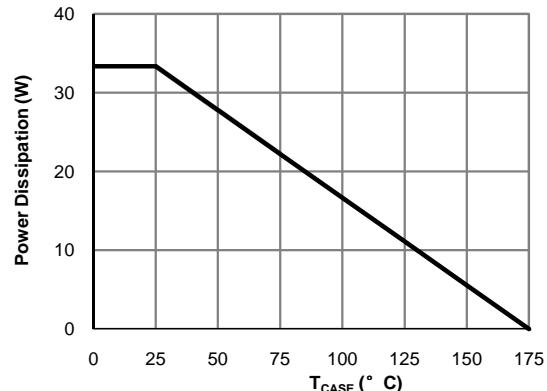


Figure 16: Power De-rating for AOTF298L (Note F)



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TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS

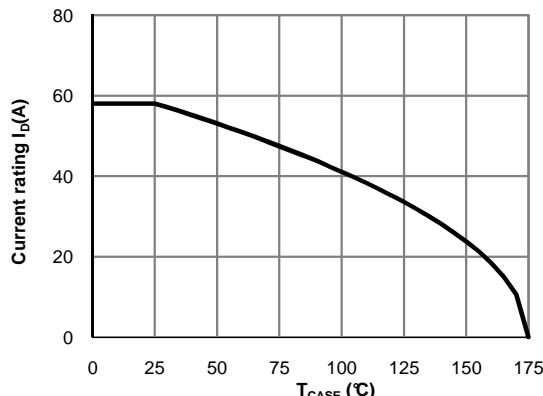


Figure 17: Current De-rating for AOT298L and AOB298L (Note F)

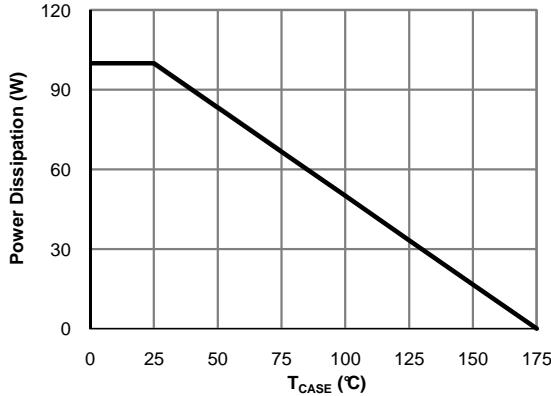


Figure 18: Power De-rating for AOT298L and AOB298L (Note F)

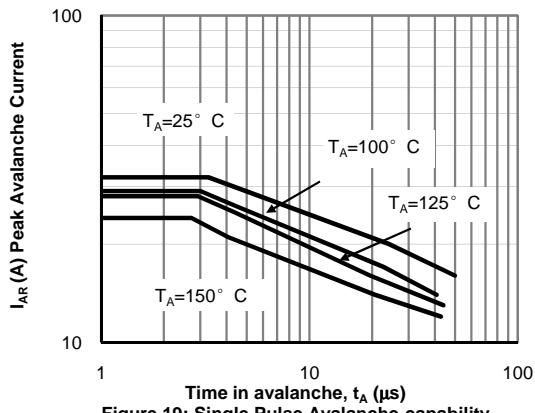


Figure 19: Single Pulse Avalanche capability (Note C)

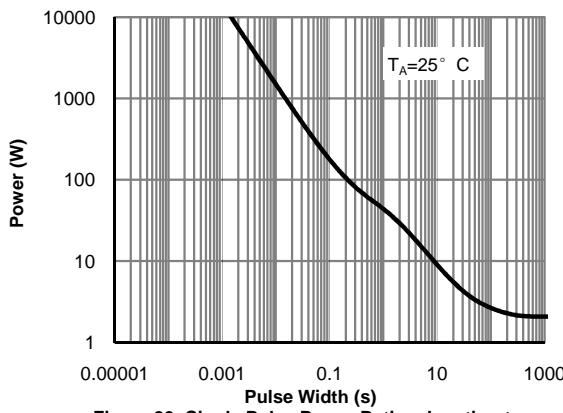


Figure 20: Single Pulse Power Rating Junction-to-Ambient (Note H)

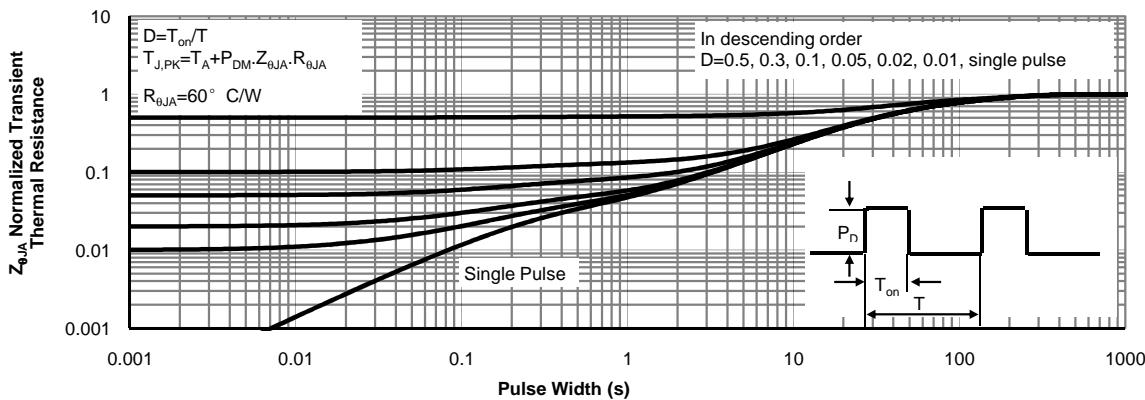
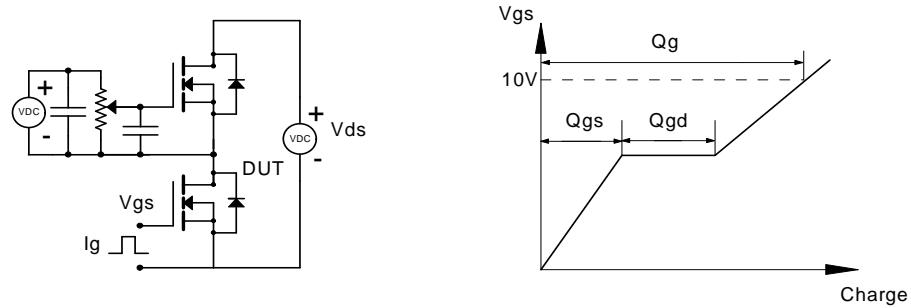
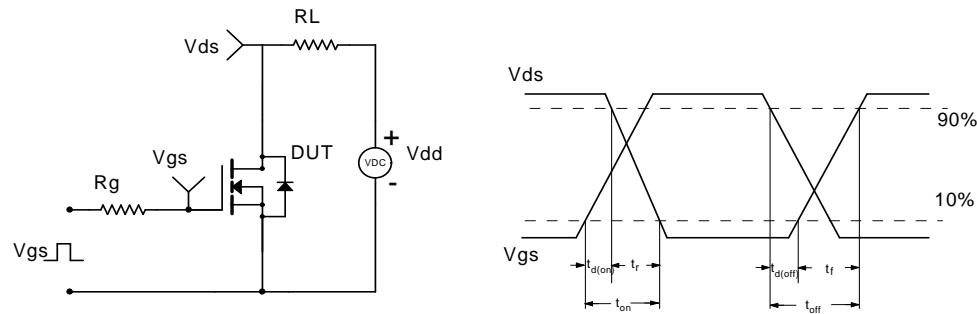


Figure 21: Normalized Maximum Transient Thermal Impedance (Note H)

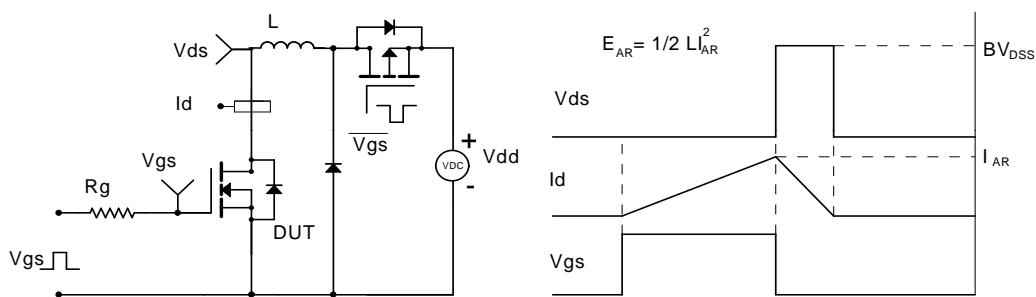
Gate Charge Test Circuit & Waveform



Resistive Switching Test Circuit & Waveforms



Unclamped Inductive Switching (UIS) Test Circuit & Waveforms



Diode Recovery Test Circuit & Waveforms

